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Figure 1A

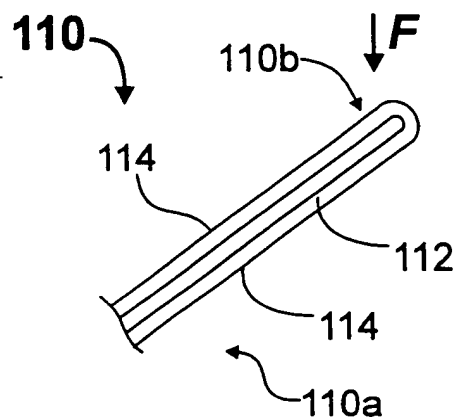


Figure 1B

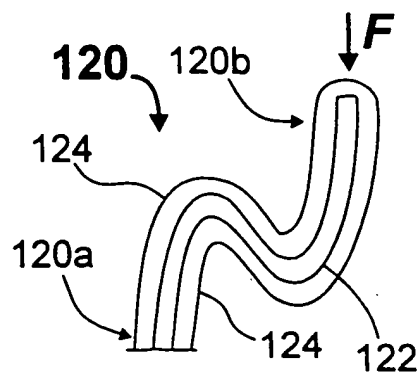


Figure 1C

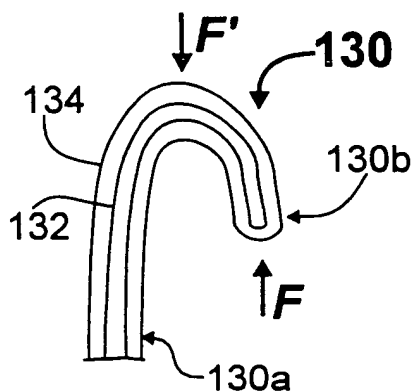


Figure 1D

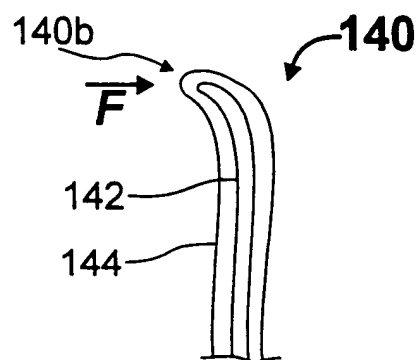


Figure 1E

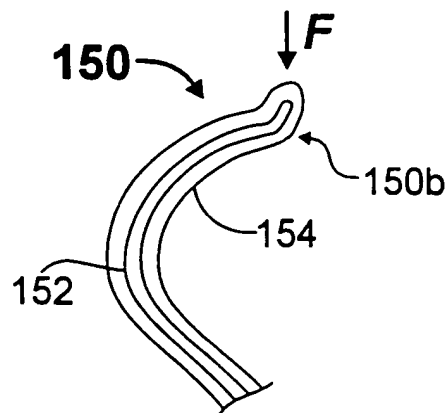


FIG. 1A

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Figure 2A

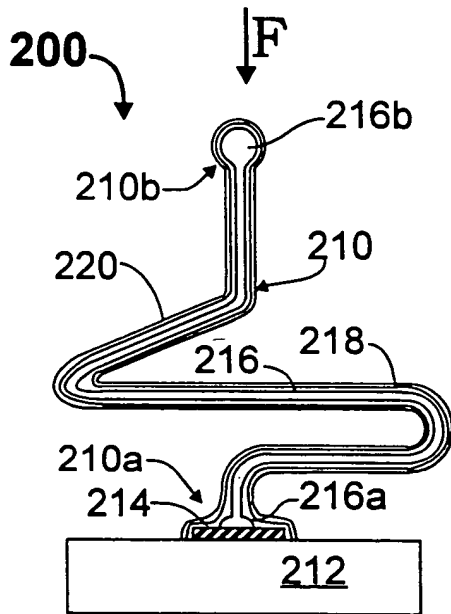


Figure 2B

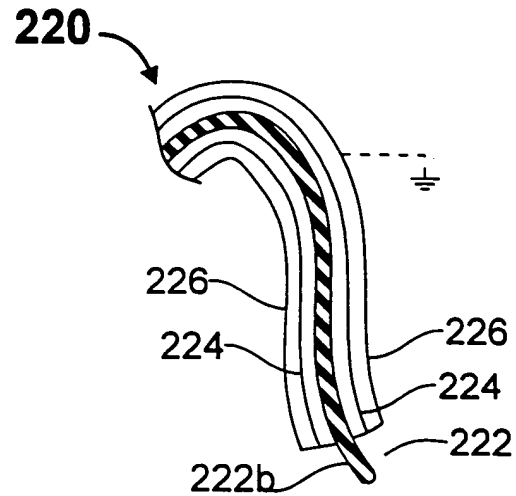
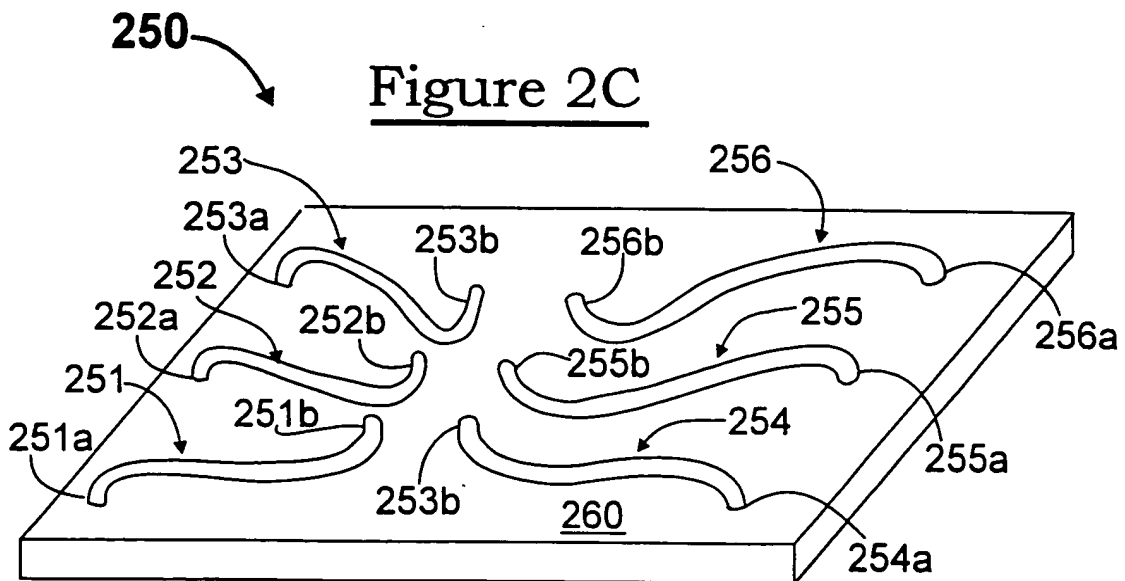


Figure 2C



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Figure 2D

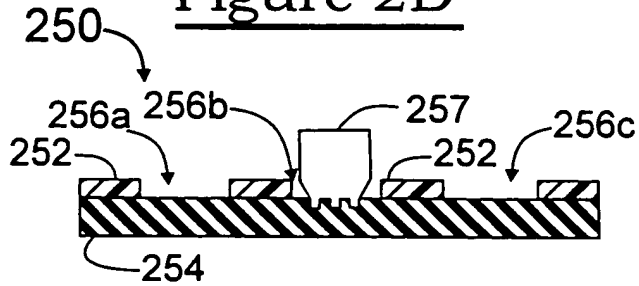


Figure 2E

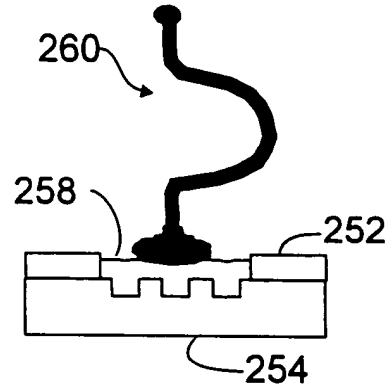


Figure 2F

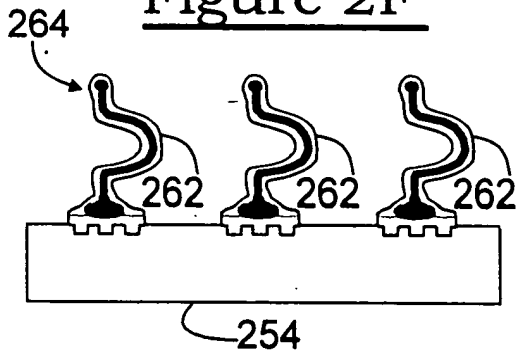


Figure 2G

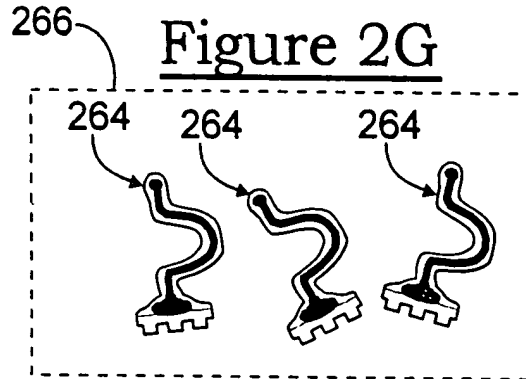


Figure 2H

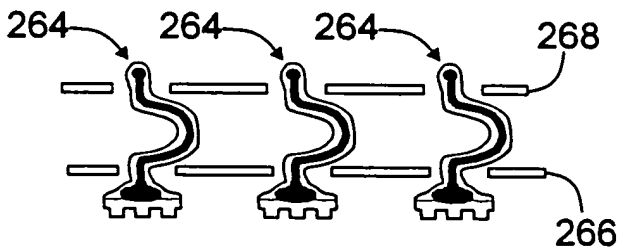
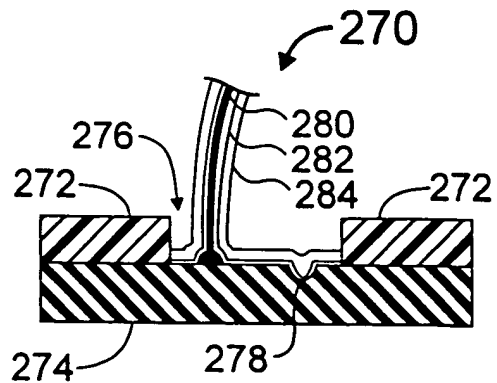


Figure 2I



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Figure 3A

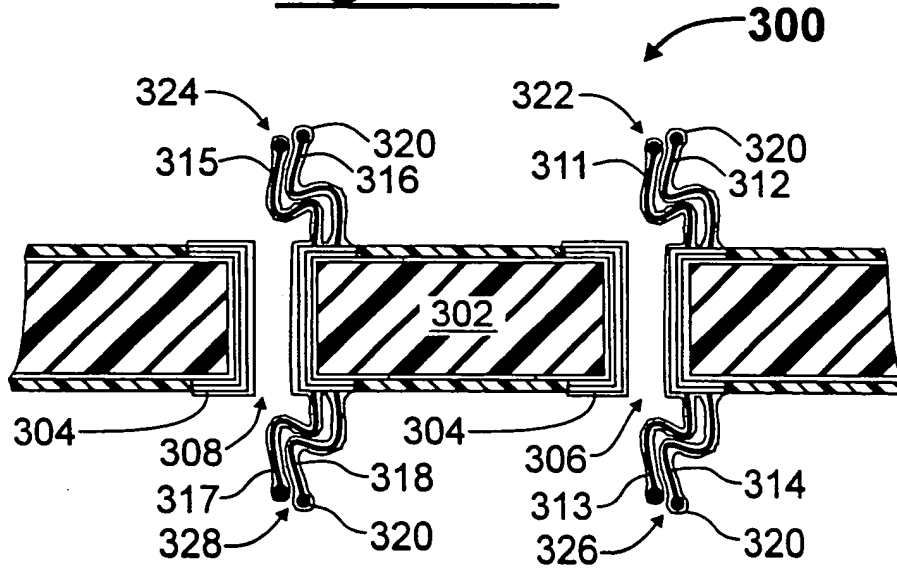


Figure 3B

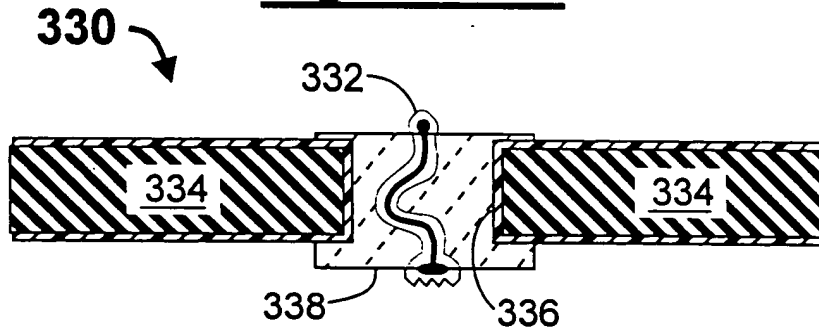
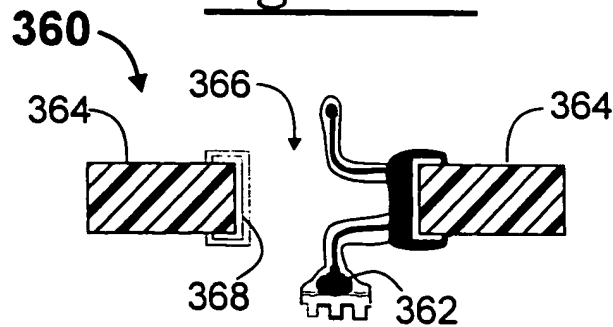


Figure 3C



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Figure 4

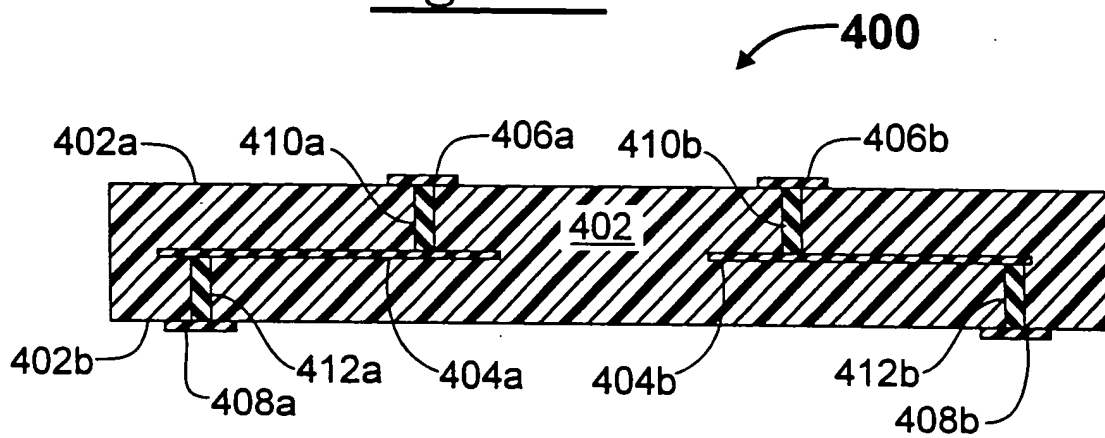
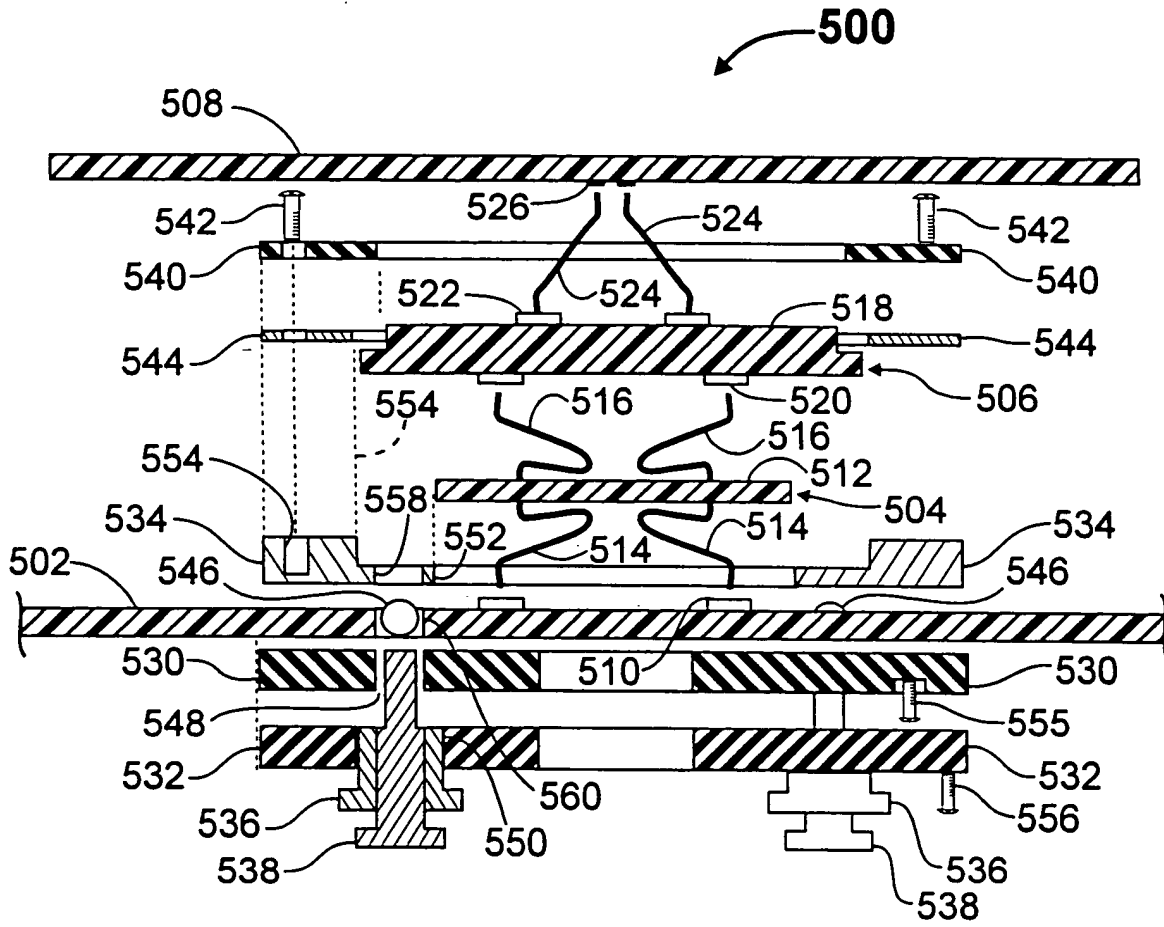


FIG. 4 is a cross-sectional view of the probe card assembly 400.

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Figure 5



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Figure 5A

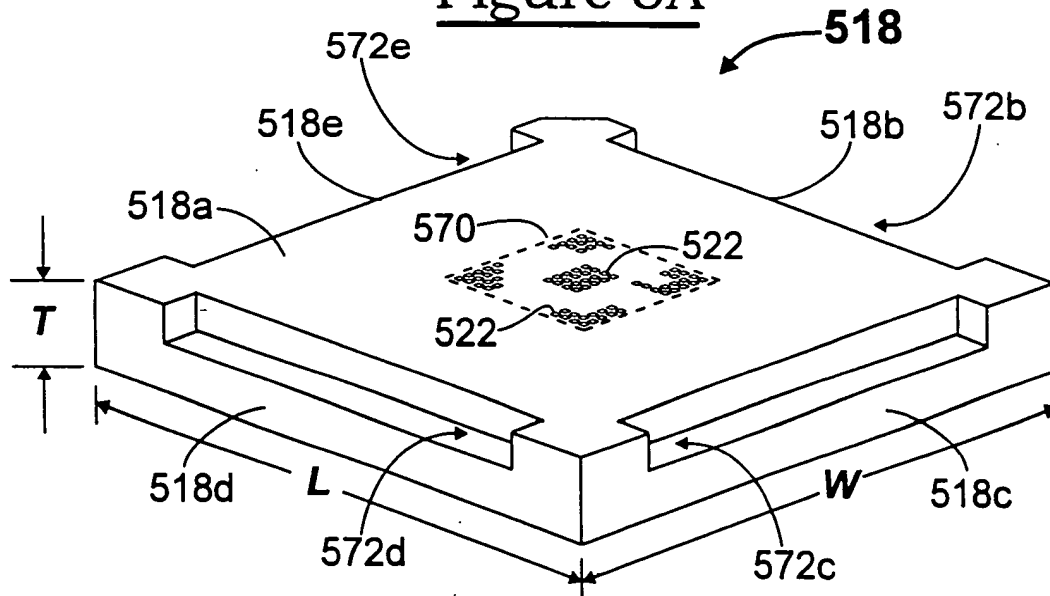
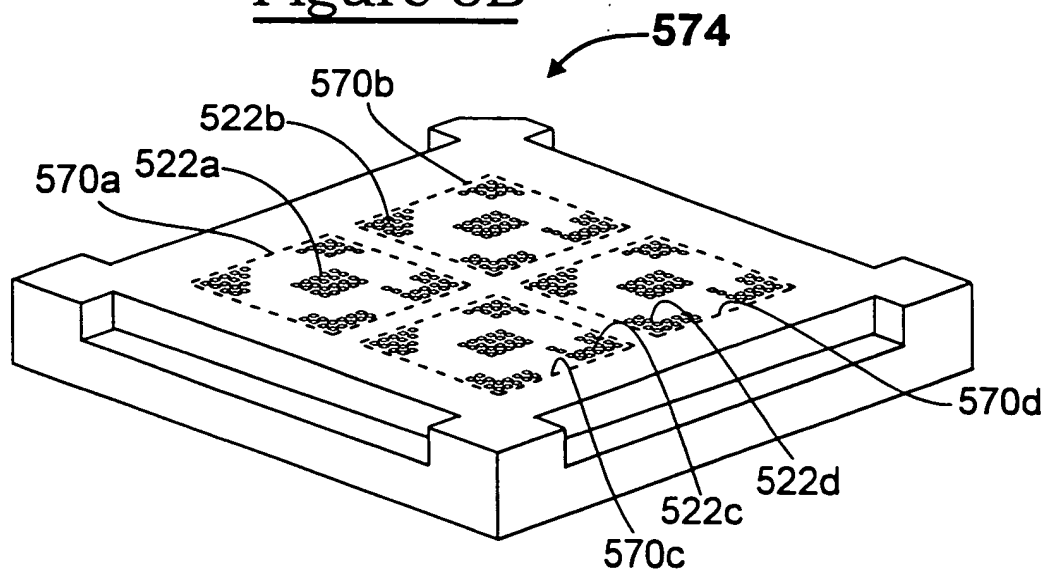
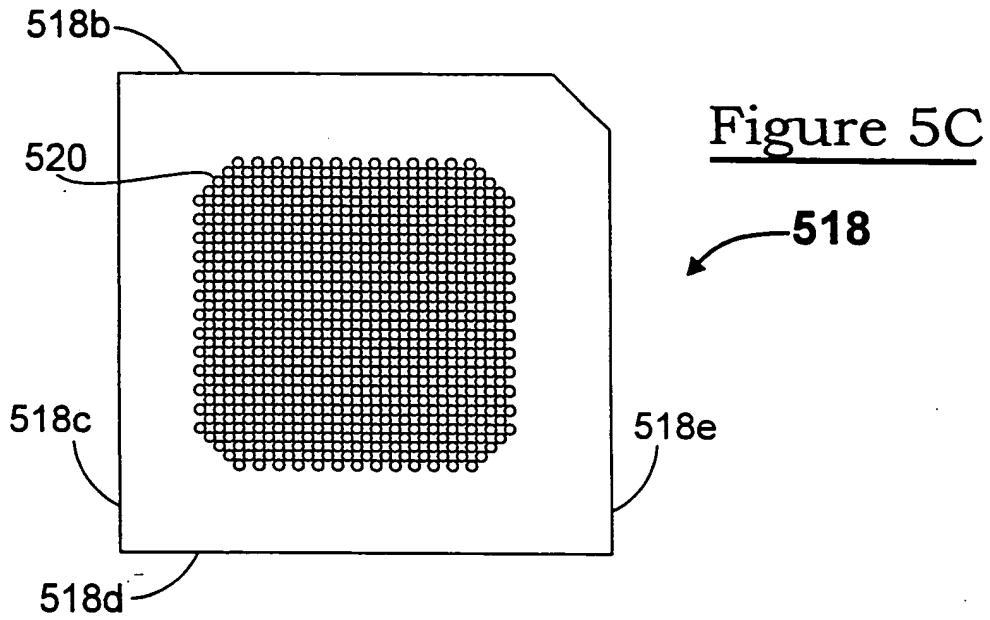


Figure 5B

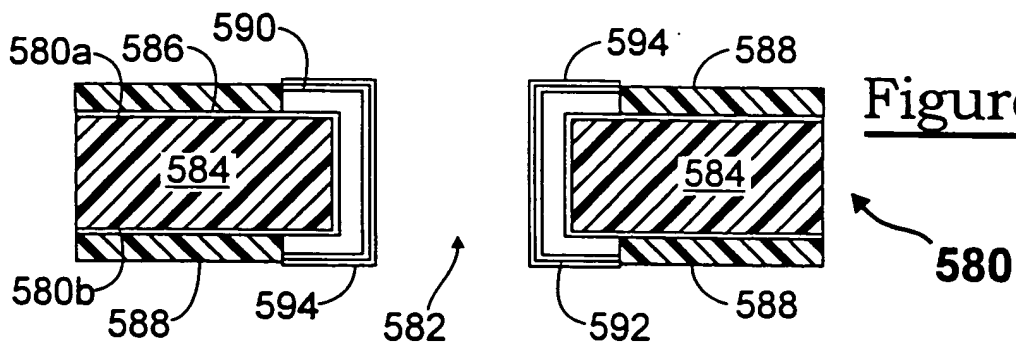
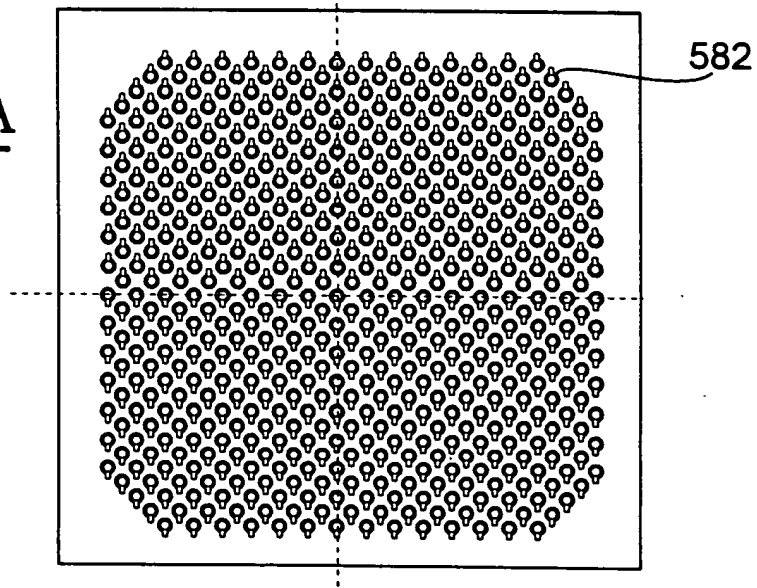


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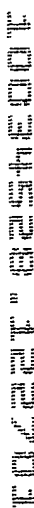
**Figure 6A**

580





700



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Figure 7A

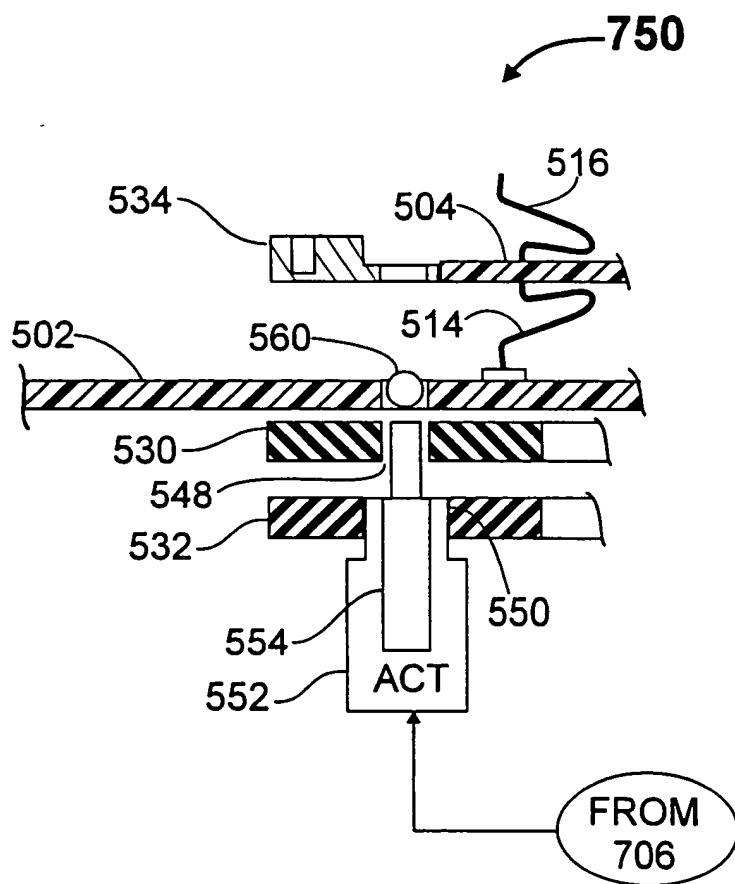


FIG. 7A

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Figure 8A

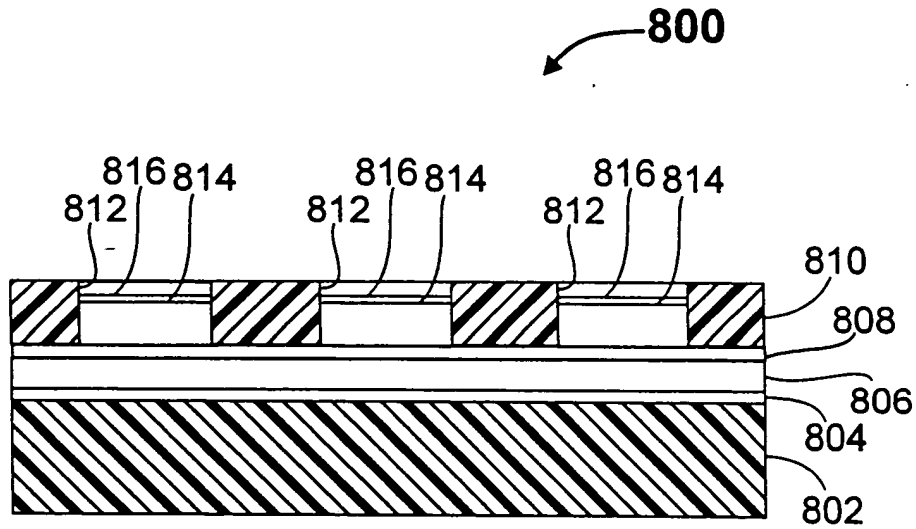
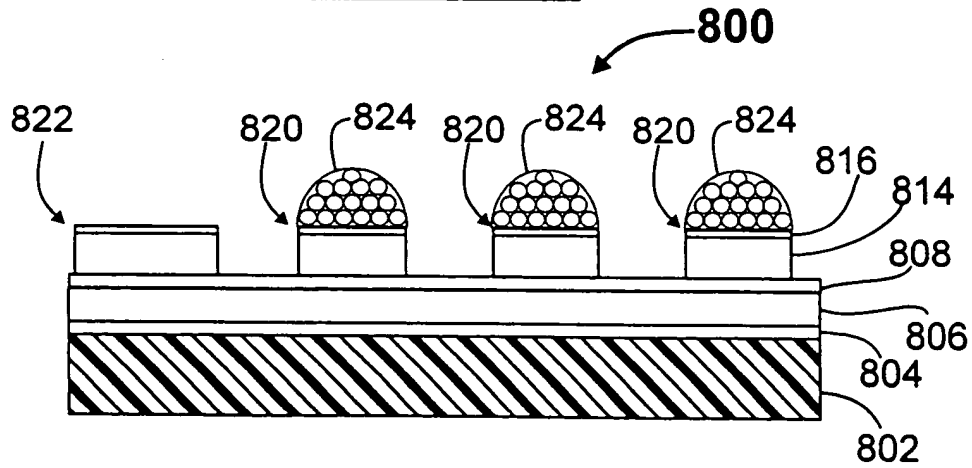


Figure 8B



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Figure 8C

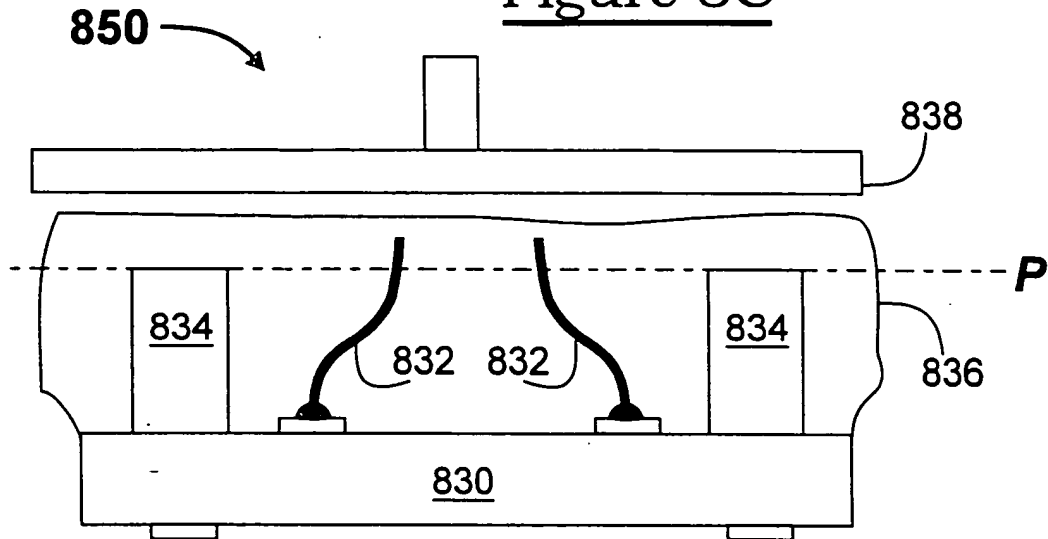


Figure 8D

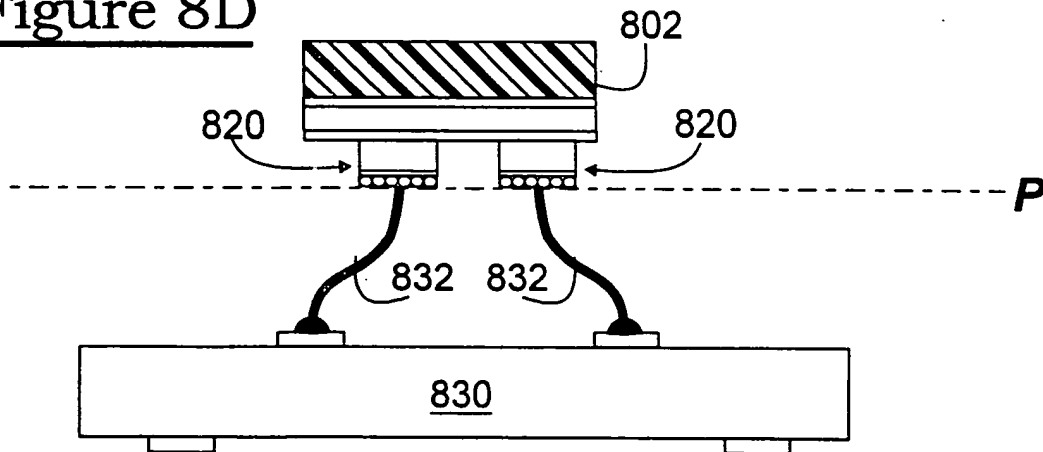


Figure 8E

